

IEC QUALITY ASSESSMENT SYSTEM (IECQ)

covering Electronic Components, Assemblies, Related Materials and Processes

For rules and details of the IECQ visit www.iecq.org

Schedule of Scope to Certificate of Approval

Independent Testing Laboratory
IECQ Certificate No.: IECQ-L ULTW 16.0003-04

CB Certificate No.: 20003698 ITL

Schedule Number: IECQ-L ULTW 16.0003-04-S Rev No.: 8 Revision Date: 2024/02/10 Page 1 of 3

Appendix-1 (20003698 ITL) Schedule of Scope to Certificate of Approval

Description test	Standard
High Temperature Operation Life test (HTOL)	IEC 60068-2-1, JESD22-A108
Low Temperature Operation Life test (LTOL)	IEC 60068-2-1, JESD22-A108
Early Life Failure Rate (ELFR)	JESD22-A-108, AEC-Q100-008
Bias Life test (BLT)	JESD22-A108
Temperature Cycling test (TCT)	JESD22-A104
Temperature variation test (TCC)	IEC 60068-2-14/33
Thermal Shock test (TST)	JESD22-A106
High Temperature Storage test (HTST)	IEC 60068-2-2, JESD22-A103
Low Temperature Storage test (LTST)	IEC 60068-2-1, JESD22-A119
Pressure Cooker test (PCT/UB-HAST)	JESD22-A102, JESD22-A118
Highly Accelerated Stress test (HAST)	JESD22-A110
Temperature and Humidity Storage test (THST)	IEC 60068-2-3, JEDEC22 A101
Temperature and Humidity with Bias test (THB)	JESD22-A101
Pre-conditioning test	JESD22-A113
Reflow test	J-STD-020
Solderability test	J-STD-002
Steam aging test	J-STD-002

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Description test	Standard
Surface Mount Technology (SMT)	IPC-A-610, IPC-A-600
Multi-function material test (Bending test)	JESD22-B113
Drop test	ISTA 2A, IEC 60068-2-32
Vibration test and Shock Test	IEC 60068-2-6/27/29/34/64
Salt atmosphere street test	JESD22-A107, IEC 60068-2-11/52
Gas corrosion test	IEC 60068-2-42/43/49/60
Electro-migration test	IPC TM650 2.6.25
Conductive resistance test	IPC 9701
Low temperature/ low humidity test	IEC 60068-2-38/39
Low pressure / altitude test	IEC 60068-2-13
Dust and water proof test	IEC 60529
Solar radiation test	IEC 60068-2-5/9
Tumbling Test	IEC 60068-2-31
Torque test	T-REL-3
Carton Compression test	ISTA 2A, ASTM
High Temperature Reverse Bias (HTRB)	MIL-STD-750 Method 1039

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Description test	Standard
High Humidity High Temperature Reverse Bias (H3TRB)	JESD22-A-101
High Temperature Gate Bias (HTGB)	JESD22-A-108
Intermittent Operational Life (IOL)	MIL-STD-750 Method 1037

Technical Reviewer of DQS: Date: 2/10/2024

